

Application/Control No.	Applicant(s)/Patent under Reexamination
10/552,353	INOUE ET AL.
Examiner	Art Unit

2836

Ronald W. Leja

SEARCHED					
Class	Subclass	Date	Examiner		
updated		7/8/2007	RWL		
338	21	7/8/2007	RWL		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
338	21	7/8/2007	RWL	
361	127	7/8/2007	rwl	
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SEARCH N (INCLUDING SEARC)
	DATE	EXMR
see attached text search	7/9/2007	RWL
checked US 2005/0195549	7/9/2007	RWL